

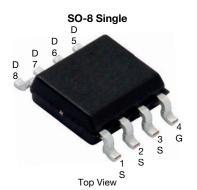
## P-Channel 30 V (D-S) MOSFET

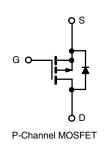
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	-30				
$R_{DS(on)}$ max. ( $\Omega$ ) at $V_{GS} = 10 \text{ V}$	0.0050				
$R_{DS(on)}$ max. ( $\Omega$ ) at $V_{GS} = 4.5 \text{ V}$	0.0080				
Q <sub>g</sub> typ. (nC)	27				
I <sub>D</sub> (A)	18				
Configuration	Single				

#### **FEATURES**

- TrenchFET® Gen IV p-channel power MOSFET
- Enables higher power density
- 100 % R<sub>q</sub> and UIS tested







#### **APPLICATIONS**

- Battery management in mobile devices
- Adapter and charger switch
- Battery switch
- · Load switch

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V <sub>DS</sub>	-30	V	
Gate-source voltage		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		-18		
Continuous dusin surrent (T. 150 °C)	T <sub>C</sub> = 70 °C	1 . 🗀	-13		
Continuous drain current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-11		
	T <sub>A</sub> = 70 °C		-8	^	
Pulsed drain current (t = 100 μs)		I <sub>DM</sub>	-145	Α	
Continuous source-drain diode current	T <sub>C</sub> = 25 °C		-5		
	T <sub>A</sub> = 25 °C	IS IS	-2.8 b, c		
Single pulse avalanche current	L = 0.1 mH	I <sub>AS</sub>	-25		
Single pulse avalanche energy	L = U. I IIIH	E <sub>AS</sub>	31.2	mJ	
Maximum power dissipation	T <sub>C</sub> = 25 °C		5.6		
	T <sub>C</sub> = 70 °C	Т. Г	3.6	w	
	T <sub>A</sub> = 25 °C	I <sub>P</sub>	3.1 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C	1 -	2 b, c		
Operating junction and storage temperature range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Soldering recommendations (peak tempera		260	-0		

THERMAL RESISTANCE RATINGS							
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT			
Maximum junction-to-ambient <sup>b</sup>	t ≤ 10 s	$R_{thJA}$	34	40	°C/W		
Maximum junction-to-case (drain)	Steady state	R <sub>thJF</sub>	18	22	- C/VV		

## Notes

- Notes
  a. Package limited
  b. Surface mounted on 1" x 1" FR4 board
  c. t = 10 s
  d. The SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
- Rework conditions: manual soldering with a soldering iron is not recommended for leadless components Maximum under steady state conditions is 85 °C/W
- g.  $T_C = 25$  °C



PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-source breakdown voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-30	-	-	V	
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = -10 mA	-	-17	-		
V <sub>GS(th)</sub> temperature coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = -250 μA	-	5.5	-	mV/°C	
Gate-source threshold voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	-1	-	-2.2	V	
Gate-source leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = +16 \text{ / } -20 \text{ V}$	-	-	100	nA	
<b>7</b>	,	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μΑ	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = -30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 70 °C	-	-	-15		
On-state drain current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	-40	-	-	Α	
Drain actives on state registeres a	Б	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -15 A	-	0.0050	-	Ω	
Drain-source on-state resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -4.5 \text{ V}, I_D = -10 \text{ A}$	-	0.0080	-		
Forward transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = -15 V, I <sub>D</sub> = -15 A	-	81	-	S	
Dynamic <sup>b</sup>							
Input capacitance	C <sub>iss</sub>		-	3490	-	pF	
Output capacitance	C <sub>oss</sub>	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1420	-		
Reverse transfer capacitance	C <sub>rss</sub>		-	70	-		
Total gate charge	Qg	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -10 \text{ A}$	-	56	84	nC	
			-	27	41		
Gate-source charge	Q <sub>gs</sub>	$V_{DS}$ = -15 V, $V_{GS}$ = -4.5 V, $I_D$ =-10 A	-	9.4	-		
Gate-drain charge	$Q_{gd}$		-	8.2	-		
Gate resistance	$R_g$	f = 1 MHz	1.5	3.5	6	Ω	
Turn-on delay time	t <sub>d(on)</sub>		-	15	30		
Rise time	t <sub>r</sub>	$V_{DD}$ = -15 V, $R_L$ = 1.5 $\Omega$ , $I_D \cong$ -10 A,	-	6	12		
Turn-off delay time	t <sub>d(off)</sub>	$V_{GEN}$ = -10 $V$ , $R_g$ = 1 $\Omega$	-	39	78		
Fall time	t <sub>f</sub>			10	20	ne	
Turn-on delay time	t <sub>d(on)</sub>		-	34	68	- ns - -	
Rise time	t <sub>r</sub>	$V_{DD}$ = -15 V, $R_L$ = 1.5 $\Omega$ , $I_D$ $\cong$ -10 A,	-	86	172		
Turn-off delay time	t <sub>d(off)</sub>	$V_{GEN}$ = -4.5 $V$ , $R_g$ = 1 $\Omega$	-	31	62		
Fall time	t <sub>f</sub>		-	22	44		
Drain-Source Body Diode Characterist	ics						
Continuous source-drain diode current	Is	T <sub>C</sub> = 25 °C	-	-	-5	Α	
Pulse diode forward current	I <sub>SM</sub>		-	-	-150	_ A	
Body diode voltage	V <sub>SD</sub>	I <sub>S</sub> = -5 A, V <sub>GS</sub> = 0 V	-	-0.73	-1.1	V	
Body diode reverse recovery time	t <sub>rr</sub>		-	44	88	ns	
Body diode reverse recovery charge	Q <sub>rr</sub>	L = 10 A di/dt = 100 A// = T = 05 °C	-	41	82	nC	
Reverse recovery fall time	ta	$I_F = -10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	19	-	no	
Reverse recovery rise time	t <sub>b</sub>		-	25	-	ns	

#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

0.015

0.012

0.009

0.006

0.003

0

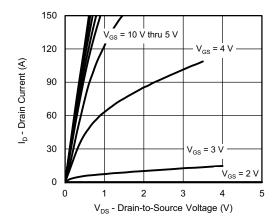
0

20

R<sub>DS(on)</sub> - On-Resistance (Ω)



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



#### **Output Characteristics**

V<sub>GS</sub> = 4.5 V

V<sub>GS</sub> = 10 V

60

80

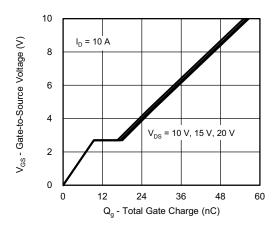
100



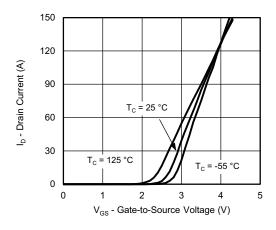
On-Resistance vs. Drain Current and Gate Voltage

I<sub>D</sub> - Drain Current (A)

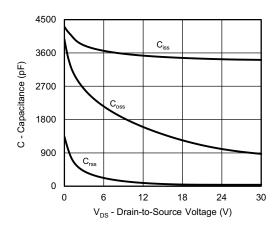
40



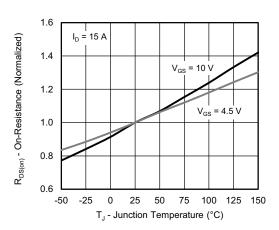
**Gate Charge** 



**Transfer Characteristics** 



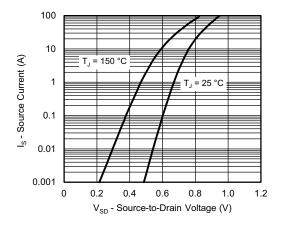
Capacitance



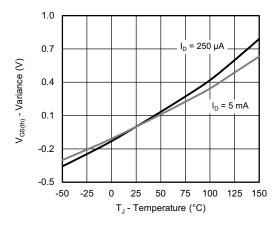
On-Resistance vs. Junction Temperature



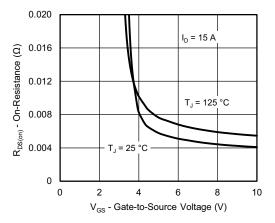
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



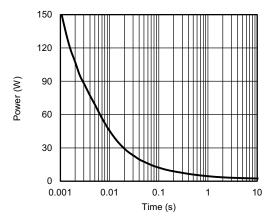
Source-Drain Diode Forward Voltage



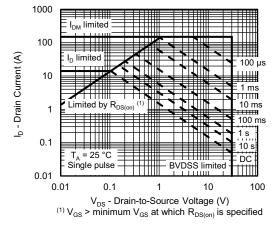
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



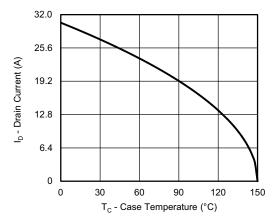
Single Pulse Power, Junction-to-Ambient



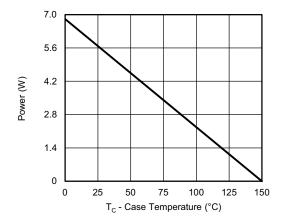
Safe Operating Area, Junction-to-Ambient

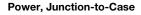


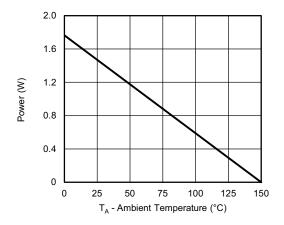
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



#### Current Derating a







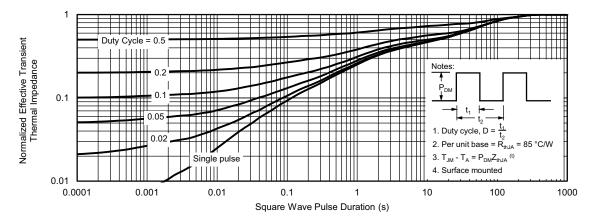
Power, Junction-to-Ambient

#### Note

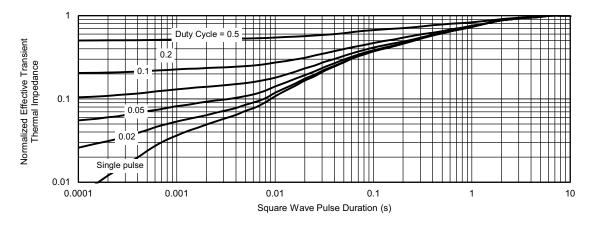
a. The power dissipation  $P_D$  is based on  $T_J$  max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



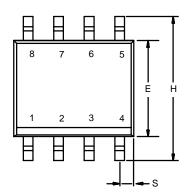
Normalized Thermal Transient Impedance, Junction-to-Ambient

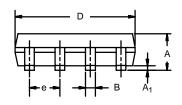


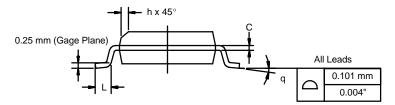
Normalized Thermal Transient Impedance, Junction-to-Case



**SOIC (NARROW): 8-LEAD**JEDEC Part Number: MS-012







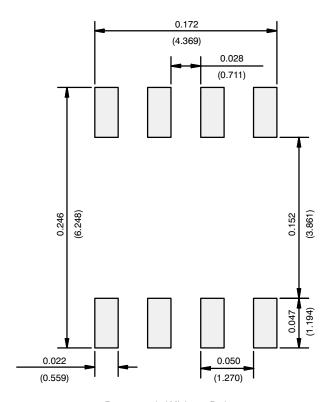
	MILLIN	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FON 0.00507 Park 1.44 Our 00					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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